

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/593,796 AMBO ET AL.	
		Examiner	Art Unit XIAOLIANG CHEN	2841 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,780,957 A	11-1988	Shiga et al.	29/830
*	B	US-4,867,691 A	09-1989	Eck, Michael P.	439/82
*	C	US-4,937,932 A	07-1990	Ishii, Toshihiro	29/622
*	D	US-4,950,170 A	08-1990	Miller, Jr., Grady A.	439/74
*	E	US-5,017,145 A	05-1991	Kanai et al.	439/45
*	F	US-5,434,749 A	07-1995	Nakayama, Yoshiaki	361/775
*	G	US-5,456,608 A	10-1995	Rogers et al.	439/48
*	H	US-5,718,057 A	02-1998	Rosli et al.	33/617
*	I	US-5,836,582 A	11-1998	Ogawa et al.	271/12
*	J	US-6,265,842 B1	07-2001	Hard et al.	318/466
*	K	US-2003/0102357 A1	06-2003	Downes, Stuart D.	228/180.1
*	L	US-6,995,650 B2	02-2006	Hayashi et al.	338/162
*	M	US-7,099,155 B2	08-2006	Kobayashi et al.	361/719

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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